## Notice of References Cited

Application/Control No. 10/622,848	Reexamination	Applicant(s)/Patent Under Reexamination OBERSKI ET AL.		
Examiner	Art Unit			
Davienne Monbleau	2878	Page 1 of 1		

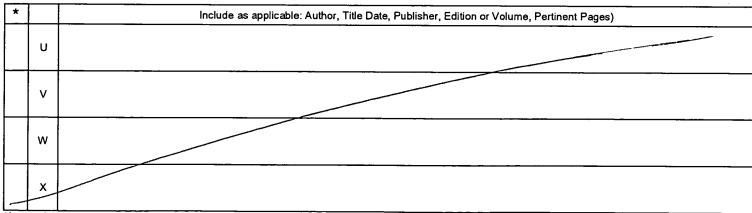
## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	А	US-2003/0053676	03-2003	Shimoda et al.	382/145
*	В	US-2004/0021877	02-2004	Clark, Bryan Kevin	356/630
*	С	US-2004/0080742	04-2004	Mizuo et al.	356/237.4
*	D	US-2002/0100872	08-2002	Hiroi et al.	250/310
*	Ε	US-6,324,298	11-2001	O'Dell et al.	382/149
*	F	US-6,876,438	04-2005	Tokita, Toshinobu	355/72
*	G	US-6,597,006	07-2003	McCord et al.	250/559.19
*	н	US-6,611,344	08-2003	Chuang et al.	356/601
*	ı	US-6,674,510	01-2004	Jasper et al.	355/55
	J	US-			
	к	US-			
	L	US-			
	M	-US-			

## **FOREIGN PATENT DOCUMENTS**

	TOREIGN PATERT DOCUMENTO								
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification			
	N								
	0								
	Р								
	Q								
	R								
	S	,							
	J								

## **NON-PATENT DOCUMENTS**



\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)

**Notice of References Cited** 

Part of Paper No. 04172005

DM 4-17-05